Abstracts

MM-wave near-field scanning resistivity microscope

M. Golosovsky and D. Davidov. "MM-wave near-field scanning resistivity microscope." 1997 MTT-S International Microwave Symposium Digest 3. (1997 Vol. III [MWSYM]): 1333-1334.

We have used a near field mm-wave scanning probe to image resistivity of different materials. We compare the near-field to the far-field imaging and find an optimal distance range for the near-field imaging.

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